

| | | | | |
|----|------------|------------|-------------|------------|
| C1 | 0.6766 (3) | 0.7342 (2) | 0.04868 (6) | 0.0240 (6) |
| C2 | 0.6738 (3) | 0.6729 (2) | 0.01080 (6) | 0.0255 (7) |
| C3 | 0.5507 (3) | 0.5207 (3) | 0.08034 (7) | 0.0241 (6) |
| C4 | 0.4240 (3) | 0.5193 (3) | 0.07648 (8) | 0.0364 (8) |

Table 2. Selected geometric parameters (Å, °)

| | | | |
|----------------------|-------------|----------------------|-----------|
| N—C1 | 1.518 (3) | C1—C2 | 1.514 (3) |
| N—C3 | 1.514 (3) | C3—C4 | 1.519 (4) |
| C1—N—C1 ¹ | 107.3 (3) | C3—N—C3 ¹ | 106.3 (3) |
| C1—N—C3 | 110.71 (15) | C2—C1—N | 115.0 (2) |
| C1—N—C3 ¹ | 110.92 (15) | N—C3—C4 | 113.9 (2) |

Symmetry code: (i) $\frac{4}{3} - x, \frac{2}{3} - x + y, \frac{1}{6} - z$.

All non-H atoms were located from direct methods. H atoms were included in the calculations as riding atoms with common isotropic displacement parameters. Methyl H atoms were allowed to rotate about C—C bonds. Reflections with *l* odd are systematically weak, giving an apparent pseudo-cell with *c* = 17.58 Å.

Data collection: *CAD-4-PC Software* (Enraf–Nonius, 1993). Cell refinement: *CAD-4-PC Software*. Data reduction: *XCAD4* (Harms, 1995). Program(s) used to solve structure: *SHELXS86* (Sheldrick, 1990). Program(s) used to refine structure: *SHELXL93* (Sheldrick, 1993). Molecular graphics: *ORTEPII* (Johnson, 1971) and *SHELXTL* (Siemens, 1995).

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Lists of atomic coordinates, displacement parameters, structure factors and complete geometry have been deposited with the IUCr (Reference: BK1293). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

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Ethyl N-Methyl-2-pyrrolylcarbonyl-hydrazinocarboxylate

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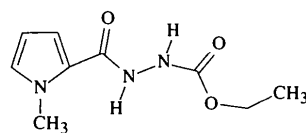
(Received 23 February 1996; accepted 31 October 1996)

Abstract

The title compound, C₉H₁₃N₃O₃, consists of an N-methyl-substituted pyrrolylcarbonyl moiety bonded at position 2 to the N' atom of a hydrazino chain.

Comment

The C—C and C—N interatomic distances in the title compound, (I), are similar to those found in other pyrrole structures (Cullen, Pepe, Meyer, Falk & Grubmayr, 1979; Fritz, Henlin, Reisen, Tschamber & Zehnderand, 1988; Ruben, Bates, Zalkin & Templeton, 1974).



(I)

The C2—O1 bond [1.232 (2) Å], a urea 'vinylogue', is slightly longer than C3—O2 [1.223 (2) Å] in the carbamate group. The C2—N2 interatomic distance is also longer than N3—C3. The torsion angle O1—C2—C2'—N1' of -8.4 (2)° (Table 1) indicates that the carbonyl group has an *s-cis* disposition with respect to the C—N bond of the pyrrole ring. The relative disposition of the pyrrolylcarbonyl and ethoxycarbonyl substituents on the hydrazine chain afford a torsion

angle C3—N3—N2—C2 of $-79.6(2)^\circ$. A perspective view of the title molecule and the arbitrary atom-labelling scheme are shown in Fig. 1.

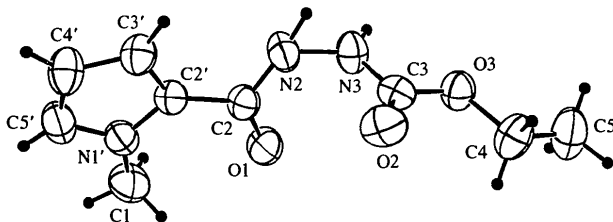


Fig. 1. View of $C_9H_{13}N_3O_3$ showing the labelling of the non-H atoms. Displacement ellipsoids are shown at the 50% probability level and H atoms are drawn as small circles of arbitrary radii.

Experimental

In the course of a study on the reactivity of 2-formylpyrroles with azodicarbonyl compounds, we found that the reaction of 1-methyl-2-formylpyrrole with diethyl azodicarboxylate in CH_2Cl_2 at 413 K in an enclosed steel reactor gives rise to the title compound with a yield of 17%. The structure inferred from elemental analysis and spectral data was confirmed by X-ray analysis and compared with the examples reported in the literature for this kind of compound generated *via* radical intermediates (Alder & Noble, 1943; Huisgen & Jacob, 1954).

Crystal data

$C_9H_{13}N_3O_3$
 $M_r = 211.22$
 Trigonal
 $P3_2$
 $a = 9.363(1) \text{ \AA}$
 $c = 11.015(2) \text{ \AA}$
 $V = 836.2(3) \text{ \AA}^3$
 $Z = 3$
 $D_x = 1.258 \text{ Mg m}^{-3}$
 D_m not measured

Mo $K\alpha$ radiation
 $\lambda = 0.71073 \text{ \AA}$
 Cell parameters from 25 reflections
 $\theta = 6-10^\circ$
 $\mu = 0.09 \text{ mm}^{-1}$
 $T = 293(2) \text{ K}$
 Cylindrical
 $0.25 \times 0.18 \times 0.18 \text{ mm}$
 Colourless

Data collection

Enraf–Nonius CAD-4 diffractometer
 $\omega-2\theta$ scans
 Absorption correction: none
 1844 measured reflections
 1844 independent reflections
 1496 reflections with $I > 3\sigma(I)$

$\theta_{\max} = 24.97^\circ$
 $h = 0 \rightarrow 11$
 $k = 0 \rightarrow 11$
 $l = -13 \rightarrow 13$
 3 standard reflections every 200 reflections
 frequency: 60 min
 intensity decay: 2.4%

Refinement

Refinement on F^2
 $R = 0.036$
 $wR = 0.046$
 $S = 1.734$
 1496 reflections
 174 parameters
 H-atom coordinates refined
 $w = 1/\sigma(F)^2$
 $(\Delta/\sigma)_{\max} = 0.060$

$\Delta\rho_{\max} = 0.333 \text{ e \AA}^{-3}$
 $\Delta\rho_{\min} = -0.137 \text{ e \AA}^{-3}$
 Extinction correction: none
 Scattering factors from *International Tables for Crystallography* (Vol. C)
 Flack parameter for absolute configuration determination = -0.1871

Table 1. Selected geometric parameters (\AA , $^\circ$)

| | | | |
|---------------|------------|----------------|------------|
| C2—C2' | 1.464 (2) | C2'—C3' | 1.385 (2) |
| C2—O1 | 1.232 (2) | N1'—C5' | 1.357 (2) |
| C2—N2 | 1.354 (2) | N1'—C1 | 1.462 (3) |
| N2—N3 | 1.377 (2) | C2'—N1' | 1.379 (2) |
| C3'—C4' | 1.396 (2) | C3—O2 | 1.223 (2) |
| O3—C3 | 1.330 (2) | C4—C5 | 1.497 (3) |
| O3—C4 | 1.456 (3) | N3—C3 | 1.349 (3) |
| C5'—C4' | 1.365 (3) | | |
| C5'—N1'—C1 | 123.1 (2) | O3—C4—C5 | 106.8 (2) |
| C2'—N1'—C1 | 128.4 (1) | C3—O3—C4 | 115.8 (1) |
| C2'—N1'—C5' | 108.2 (1) | N3—C3—O2 | 125.1 (1) |
| C3'—C4'—C5' | 107.4 (2) | O1—C2—N2 | 122.1 (1) |
| N1'—C5'—C4' | 109.3 (1) | O3—C3—O2 | 125.2 (2) |
| N1'—C2'—C3' | 107.7 (1) | C2'—C2—O1 | 123.7 (1) |
| C2—N2—N3 | 120.4 (2) | C2'—C2—N2 | 114.2 (1) |
| C2—C2'—C3' | 128.9 (1) | C3—N3—N2 | 119.9 (1) |
| C2'—C3'—C4' | 107.3 (2) | O3—C3—N3 | 109.7 (1) |
| C2—C2'—N1' | 123.3 (1) | | |
| O1—C2—C2'—N1' | -8.4 (2) | C3—O3—C4—C5 | 170.9 (2) |
| O1—C2—C2'—C3' | 169.5 (2) | C2—C2'—N1'—C5' | 178.7 (2) |
| N2—C2—C2'—N1' | 170.9 (2) | C2—C2'—N1'—C1 | -7.0 (3) |
| N2—C2—C2'—C3' | -11.2 (3) | C2—C2'—C3'—C4' | -178.3 (2) |
| C2'—C2—N2—N3 | 174.5 (1) | C1—N1'—C5'—C4' | -175.2 (2) |
| O1—C2—N2—N3 | -6.2 (2) | N2—N3—C3—O3 | 173.9 (1) |
| C4—O3—C3—N3 | -175.9 (1) | N2—N3—C3—O2 | -7.4 (2) |
| C4—O3—C3—O2 | 5.4 (2) | C3—N3—N2—C2 | -79.6 (2) |

Data collection: *CAD-4 Software* (Enraf–Nonius, 1991). Data reduction: *PROCESS* in *MolEN* (Fair, 1990). Program(s) used to solve structure: *MULTAN11/82* (Main *et al.*, 1982). Program(s) used to refine structure: *LSFM* in *MolEN*. Molecular graphics: *ORTEP* (Johnson, 1976). Software used to prepare material for publication: *SHELXL93* (Sheldrick, 1993).

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Lists of atomic coordinates, displacement parameters, structure factors and complete geometry have been deposited with the IUCr (Reference: KA1194). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

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